Improving Rocket & Flight Vehicle Testing Under Capital Constraints

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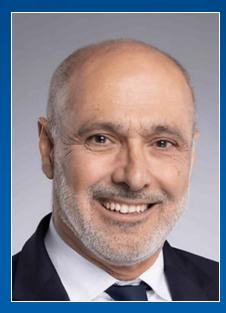














Presenters

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Overview & Objectives

Key challenges in rocket and flight vehicle testing.

The importance of leveraging HIL simulation and modular systems for efficient and budget-conscious validation testing.

Explore budget-friendly
strategies for testing key
rocket & flight vehicle systems.

Showcase solutions for overcoming testing complexities in systems for ground support, propulsion, avionics, payload systems, and bus infrastructure.



Why Efficient Testing is Crucial in Space

Critical nature of flight vehicle testing



The need for resource optimization



Why Efficient Testing is Crucial in Space

If testing misses a "minor" fault

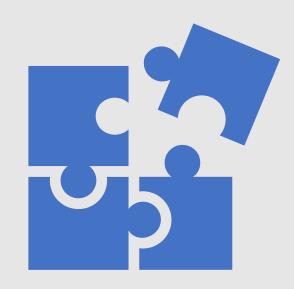


- Schedule disruptions
- Safety risks
- Spontaneous unscheduled disassembly



Why Efficient Testing is Crucial in Space

Complexity
Demands a
Strategic
Approach



Hardware-in-the-Loop Simulation





Why HIL Simulation?

- Time is Short: Execute a wide variety of tests quickly using simulation and models instead of setting up prototypes and physical test rigs.
- DUTS are More Complex: Find and fix bugs earlier in the design process to avoid defects getting out of production.
- Budgets are Tight: Testing on physical models is expensive and errors found early in the design process are significantly cheaper to correct.
- Repeatability: Test procedures can be 100% replicated to verify future control system upgrades do not impact performance.
- Safety: Can replicate extremes of operation without risk of damage to equipment or operators.

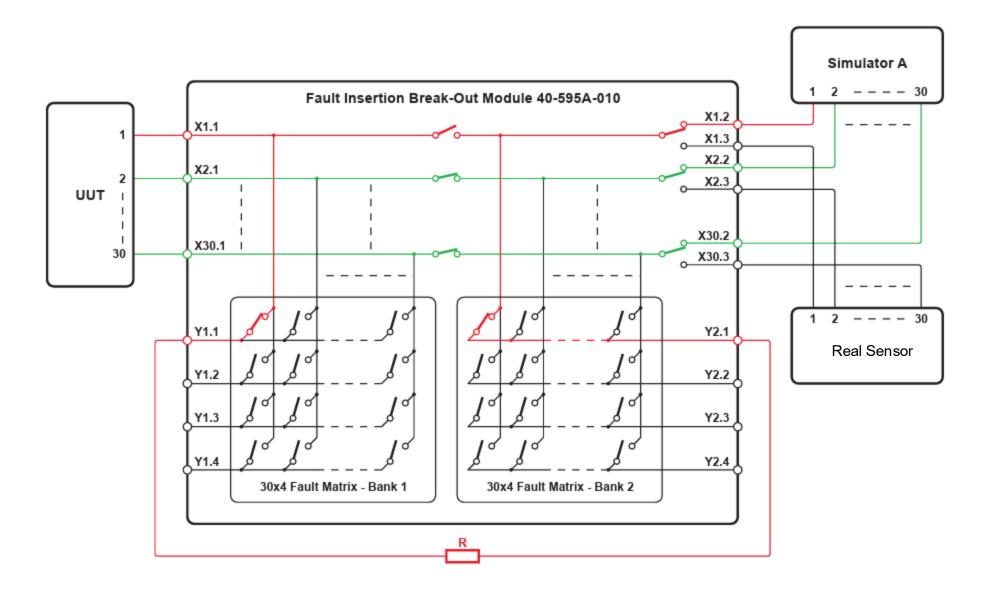


What is HIL Simulation?

- I/O from an embedded control system is connected to a tester that simulates realworld conditions
- The test system provides simulated stimulus to the embedded system
- Validating the integrity and functionality of embedded system designs (and modifications)
- Injection of fault conditions to confirm system response is as expected

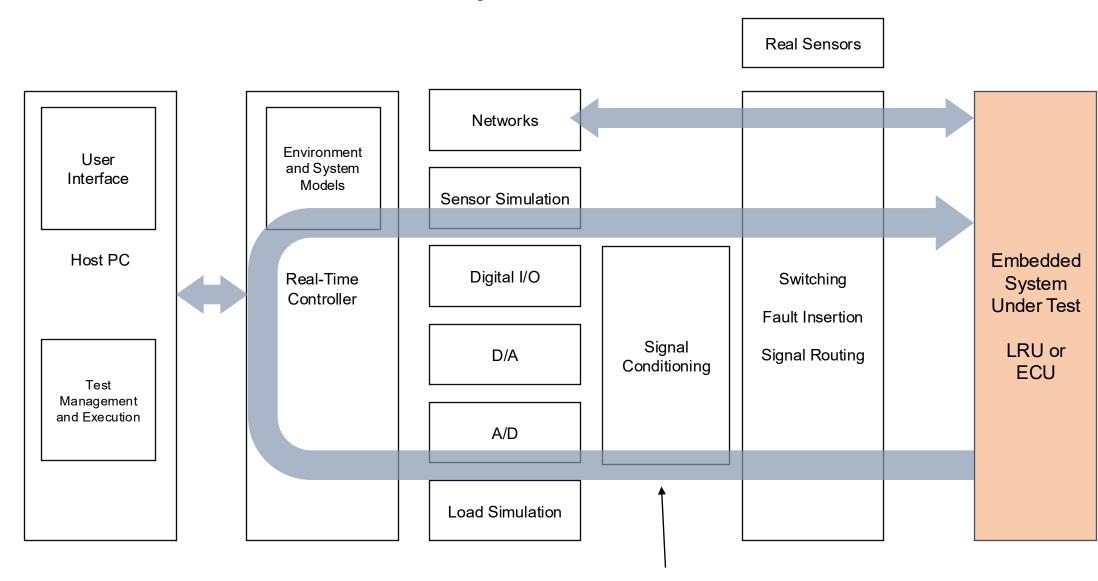


Examples of Fault Matrices

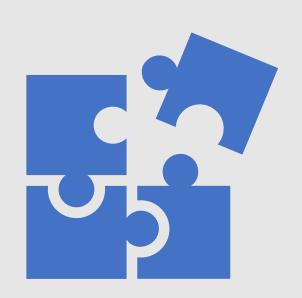




Breakdown of a HIL system







Iterative Test Development& Standardized Interfaces





Iterative Test Development

Modular systems allow engineers to adapt test setups as designs evolve, ensuring scalability and flexibility over longer timelines.





Standardized Interfaces

By aligning test equipment with common requirements, teams can seamlessly switch between different devices under test (DUT).









Step 2: Evaluate Your UUT Requirements

Subsystem 1

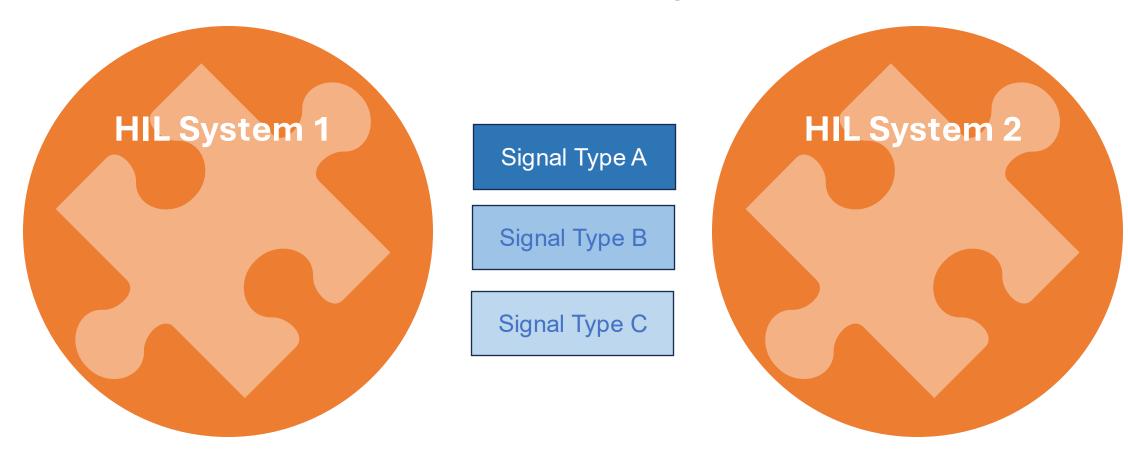
Sensor Inputs
Communication Interfaces
Power Systems
Frequencies
Fault Conditions

Subsystem 2

Sensor Inputs
Communication Interfaces
Power Systems
Frequencies
Fault Conditions

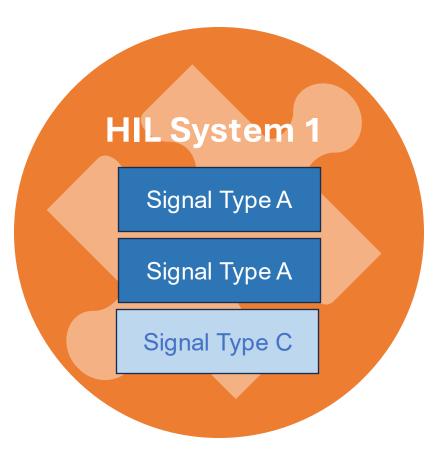


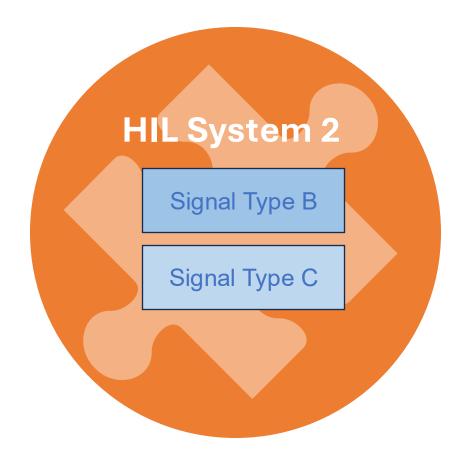
Requirement Comparison: Generate the designs for the individual modules





Common Test Equipment and Standard Interfaces

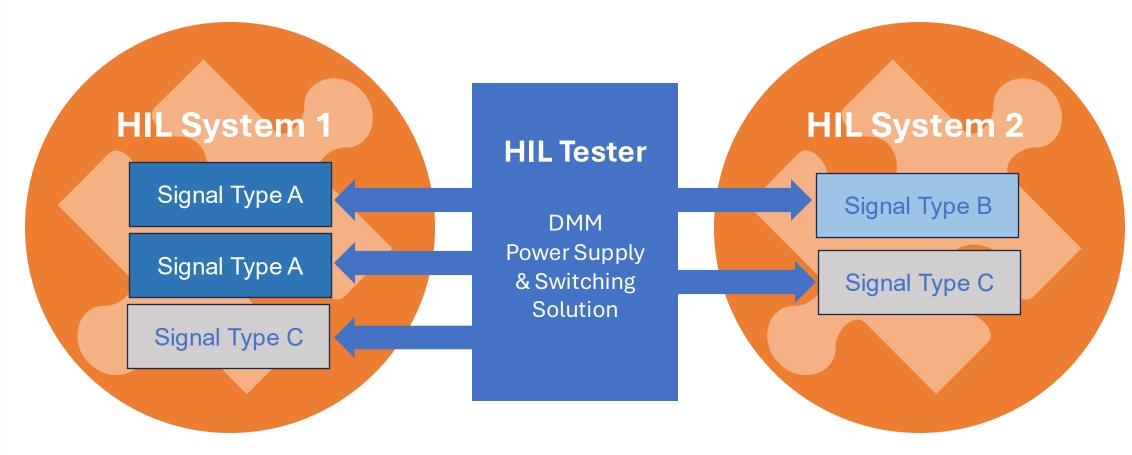






Recompose signal modules into HIL systems

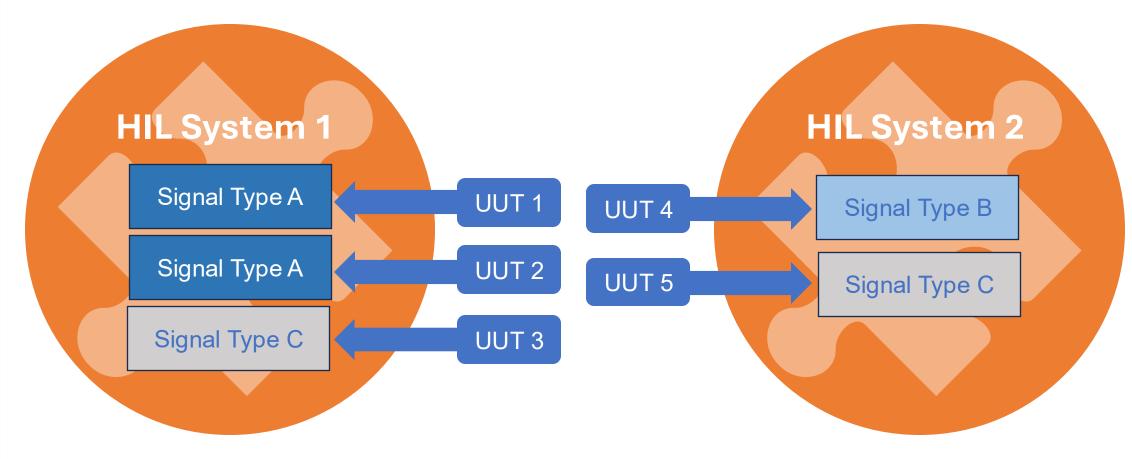
Common Test Equipment and Standard Interfaces





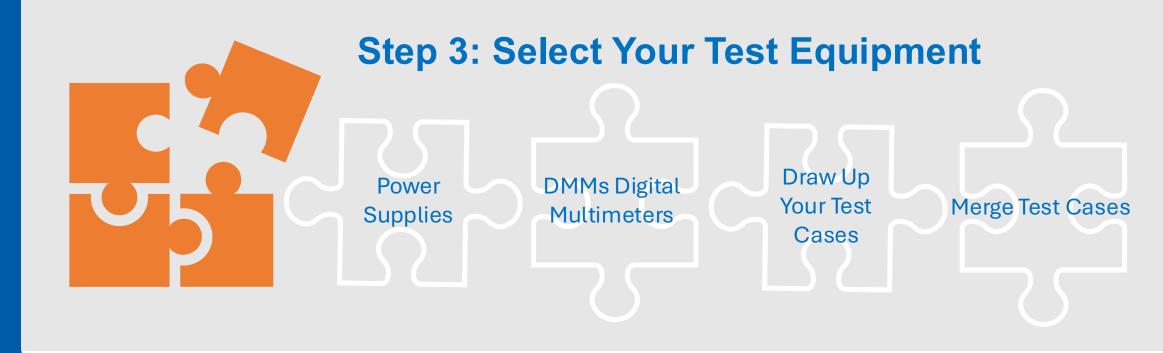
Certify the HIL is working properly before connecting to units under test (UUTs)

Common Test Equipment and Standard Interfaces

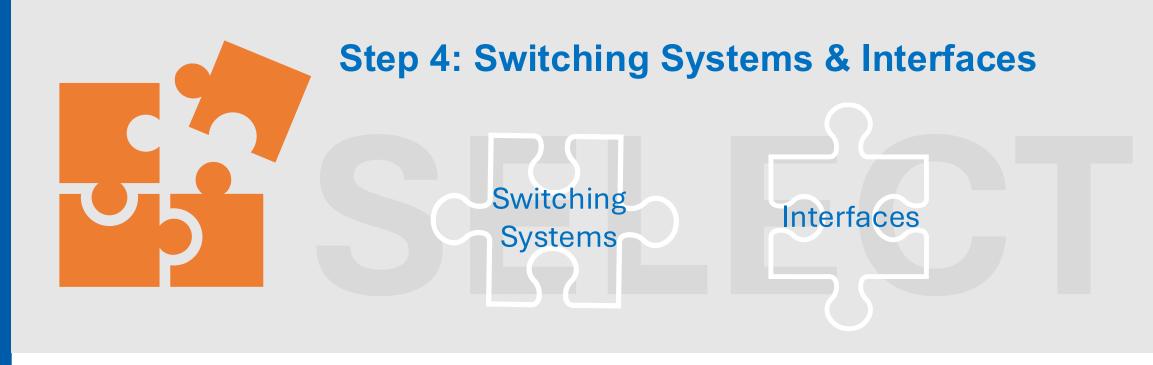




Certify the HIL is working properly before connecting to units under test (UUTs)









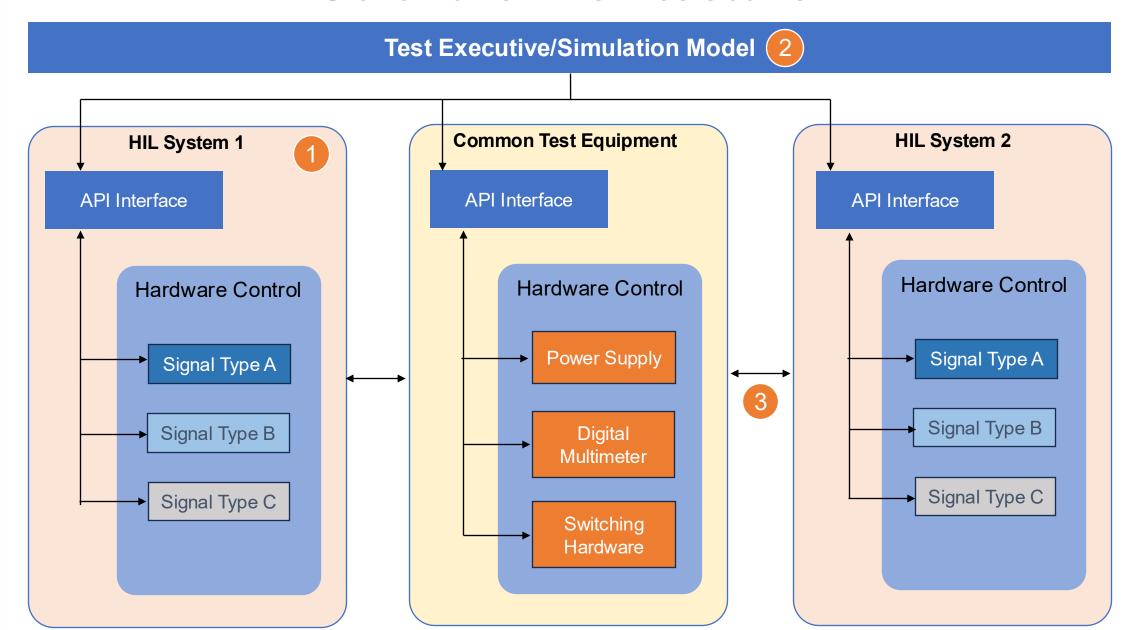


Step 5: Develop Your HIL Software Framework

- Adaptable to a wide range of needs
- Accurate logic for nominal and fault conditions
- User-friendly interface for control of HIL & components



Software Architecture





Helix SwitchCore – Configurable HIL Platform

A Configurable & Adaptable high-density multiplexing test system for System Verification/Validation and/or HIL verification

Key System Features

- Hardware Agnostic
- Non-Proprietary Software
- Low-Cost, High Impact
- Multi-Use
- High Stability Controller
- Compact "Lite" HIL



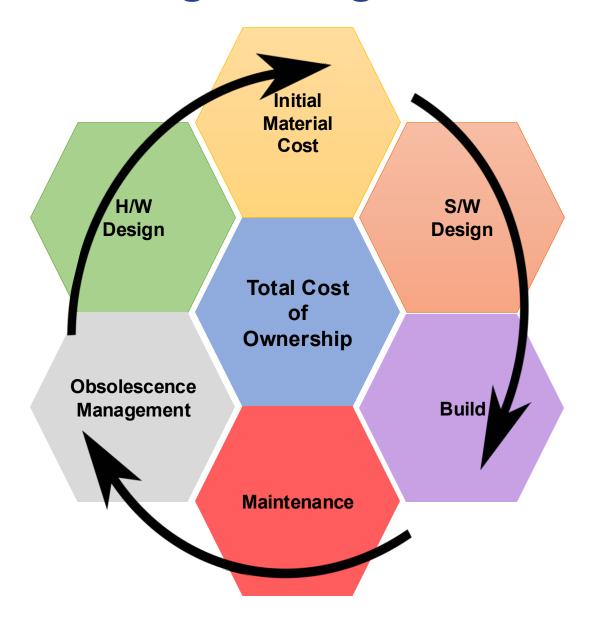


Common Challenges for Test Engineering Teams

- Limited Resources
- Compressed Schedule
- Evolving Test Requirements

The question is...

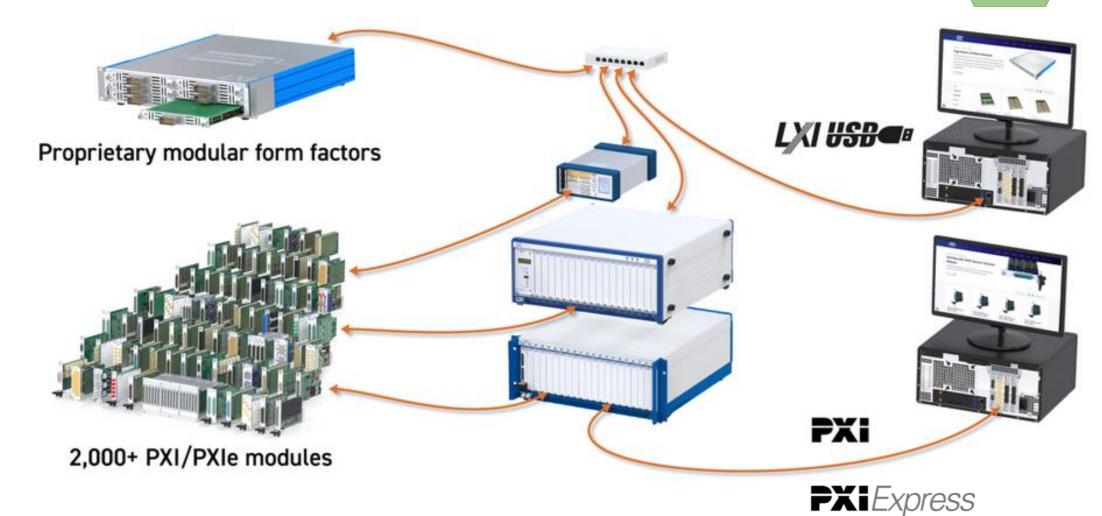
How do we employ an efficient development process that lowers the total cost of ownership?





Flexible Platform Architecture



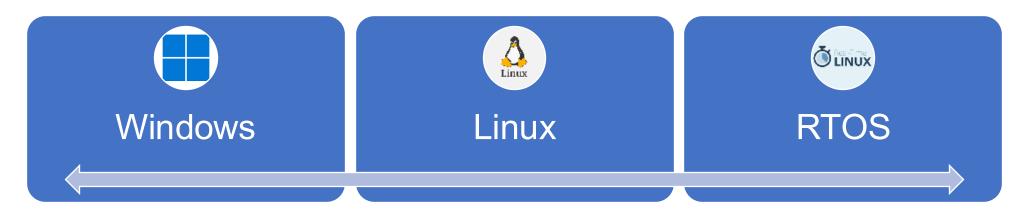




Software Flexibility



Operating System

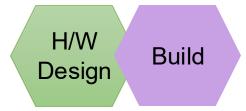


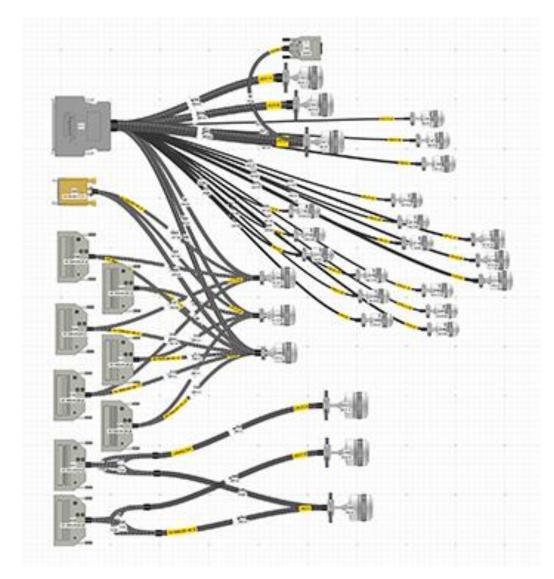
Programming Language





Expediting Cable Design/Build







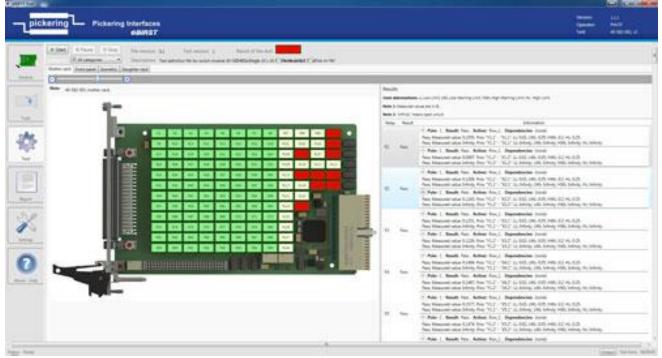
pickeringtest.com/cdt



Maintaining Switching Systems: eBIRST











- 3-Pronged Approach to Obsolescence Mitigation
 - Planning for obsolescence during the design phase
 - Using open-standard platforms
 - Designing out obsolescence whenever possible











Design with Ease

- Expert support resources and cloud-based tools
- Deep product portfolio with >2000 PXI modules
- Rapid product customization and design services



Deploy with Speed

- · Expansive IDE and OS coverage
- Productive application software
- Custom cable design and manufacture



Sustain with Confidence

- Highest quality relays
- Standard 3-year warranty with onboard spares
- 20+ year product lifecycles with free technical support





DMC/Pickering Collaboration

How we collaborate

- Present end-user with a single point-of-contact for the integrated HILS.
- Consult directly on planned uses of Pickering products.
- Get feedback or find alternate/better ways to structure things.
- Leverage use of open-platforms to maximize use of core competencies from multiple vendors.
- Provides Pickering with end-user feedback that helps drive product roadmap.

Q&A







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